

## 1. Description

This Power MOSFET is produced using KIA advanced TRENCH technology. This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

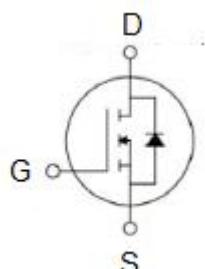
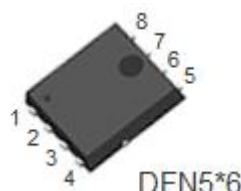
## 2. Features

- $R_{DS(ON)}=2.6\text{m}\Omega(\text{typ.}) @ V_{GS}=10\text{V}$
- Very Low On-resistance  $R_{DS(ON)}$
- Low  $C_{RSS}$
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

## 3. Application

- PWM Application
- Load Switch
- Power Management

## 3. Pin configuration



Pin	Function
4	Gate
5,6,7,8	Drain
1,2,3	Source

## 4. Ordering Information

Part Number	Package	Brand
KNY3303B	DFN5*6	KIA

## 5. Absolute maximum ratings

T<sub>C</sub>=25°C unless otherwise noted

Parameter	Symbol	Rating	Units
Drain-source voltage	V <sub>DSS</sub>	30	V
Continuous drain current	T <sub>C</sub> =25°C	I <sub>D</sub>	A
	T <sub>C</sub> =100°C	I <sub>D</sub>	A
Pulsed drain current -Pulsed <sup>1)</sup>	I <sub>DM</sub>	360	A
Gate-source voltage	V <sub>GS</sub>	±20	V
Single pulse avalanche energy <sup>2)</sup>	E <sub>AS</sub>	342	mJ
Power dissipation (T <sub>C</sub> =25°C)	P <sub>D</sub>	68	W
Operating junction and storage temperature range	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	T <sub>L</sub>	300	°C

\*Drain current limited by maximum junction temperature.

## 6. Thermal Data

Parameter	Symbol	Rating	Unit
Thermal resistance junction-case	R <sub>θJC</sub>	1.83	°C/W

## 7. Electrical characteristics

( $T_C=25^\circ\text{C}$ , unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
Drain-source leakage current	$I_{\text{DSS}}$	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-source forward leakage	$I_{\text{GSS}}$	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.2	1.5	2.5	V
Drain-source on-resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=20\text{A}$	-	2.6	3.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=15\text{A}$	-	3.5	5	$\text{m}\Omega$
Input capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}$ $f=1\text{MHz}$	-	4002	-	pF
Output capacitance	$C_{\text{oss}}$		-	438	-	pF
Reverse transfer capacitance	$C_{\text{rss}}$		-	395	-	pF
Turn-on delay time	$t_{\text{d(on)}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V}$ $R_L=3\Omega, I_{\text{D}}=30\text{A},$ $T_J=25^\circ\text{C}$ <sup>3)</sup>		15		ns
Rise time	$t_r$			19		ns
Turn-off delay time	$t_{\text{d(off)}}$			42		ns
Fall time	$t_f$			11		ns
Total gate charge(10V)	$Q_g$	$V_{\text{DS}}=15\text{V}, I_{\text{D}}=30\text{A}$ $V_{\text{GS}}=10\text{V}$ <sup>3)</sup>	-	70	-	nC
Gate-source charge	$Q_{\text{gs}}$		-	45	-	nC
Gate-drain charge	$Q_{\text{gd}}$		-	12	-	nC
Maximum Continuous Drain-Source Diode Forward Current	$I_S$	—	-	-	120	A
Maximum Pulsed Drain-Source Diode Forward Current	$I_{\text{SM}}$	—	-	-	360	A
Diode forward voltage	$V_{\text{SD}}$	$I_{\text{SD}}=30\text{A}, V_{\text{GS}}=0\text{V},$ $T_J=25^\circ\text{C}$	-	-	1.2	V
Reverse recovery time	$T_{\text{rr}}$	$I_F=30\text{A} \frac{dI}{dt}=100\text{A}/\mu\text{s}$	-	48	-	ns
Reverse recovery charge	$Q_{\text{rr}}$	$I_F=30\text{A} \frac{dI}{dt}=100\text{A}/\mu\text{s}$	-	80	-	nC

Note:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition:  $T_J=25^\circ\text{C}$ ,  $V_{\text{DD}}=30\text{V}$ ,  $V_G=10\text{V}$ ,  $R_G=25\Omega$ ,  $L=0.5\text{mH}$ ,  $I_{\text{AS}}=25\text{A}$
3. Pulse Test: Pulse Width  $\leq 300\text{us}$ , Duty Cycle  $\leq 0.5\%$

## 8. Typical Electrical Characteristics

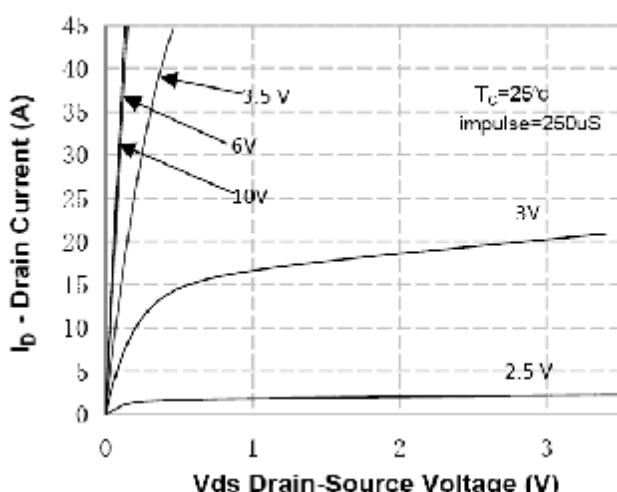


Figure 1. On-Region Characteristics

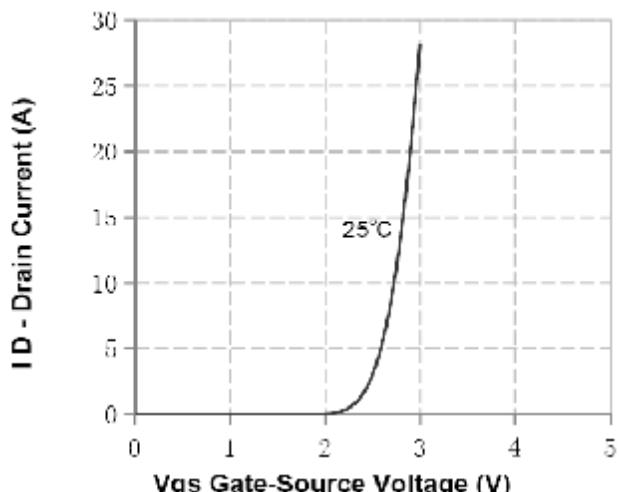


Figure 2. Transfer Characteristics

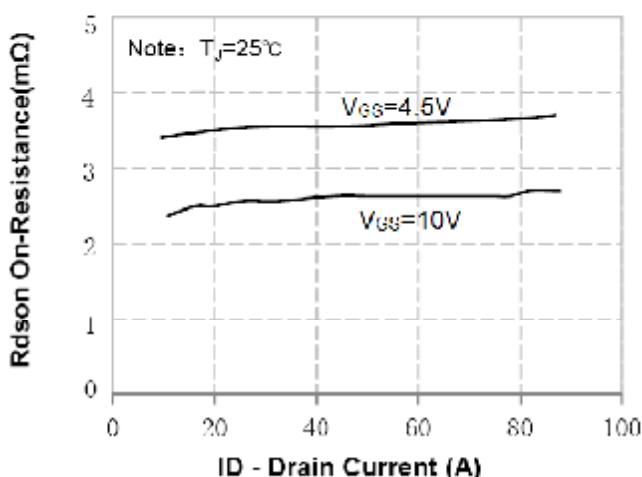


Figure 3. On-Resistance Variation vs  
Drain Current and Gate Voltage

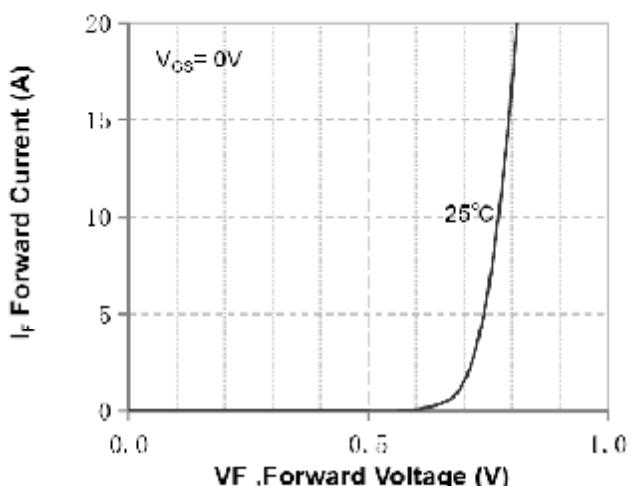


Figure 4. Body Diode Forward Voltage  
Variation with Source Current  
and Temperature

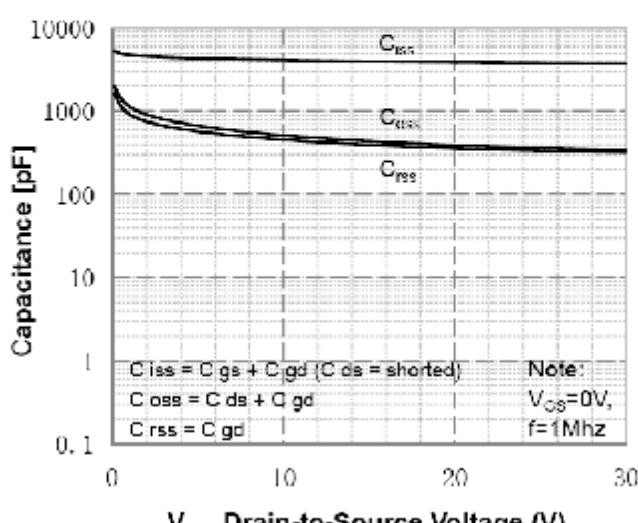


Figure 5. Capacitance Characteristics

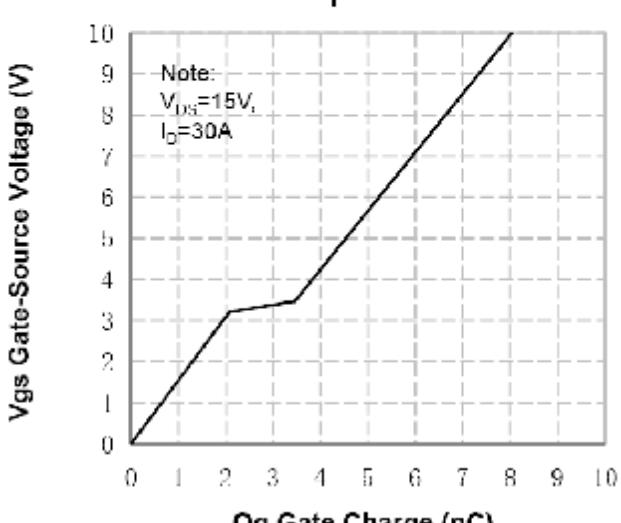
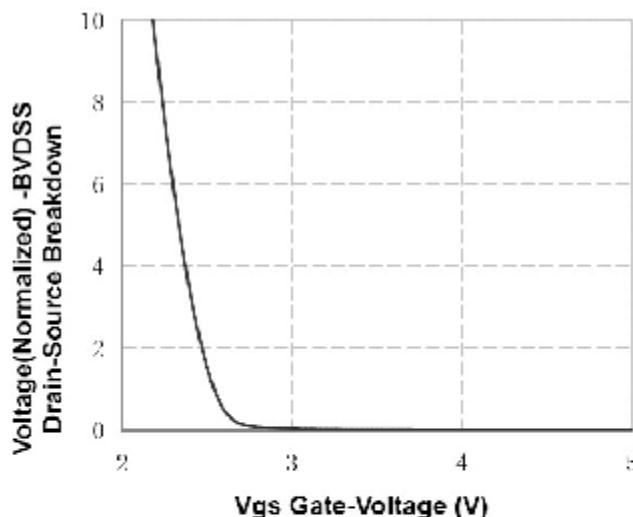
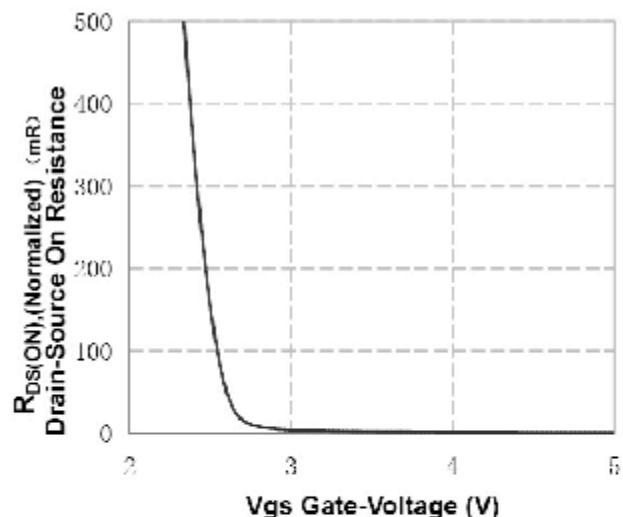


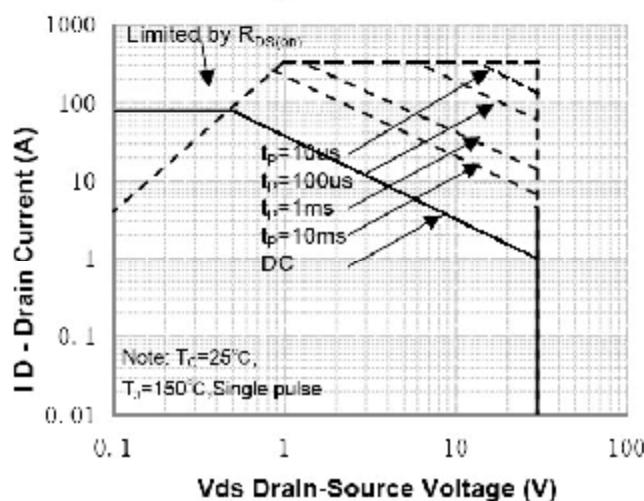
Figure 6. Gate Charge Characteristics



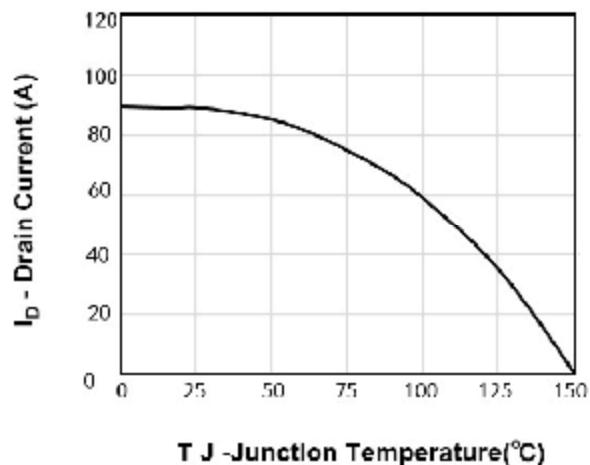
**Figure 7. Breakdown Voltage Variation vs Gate-Voltage**



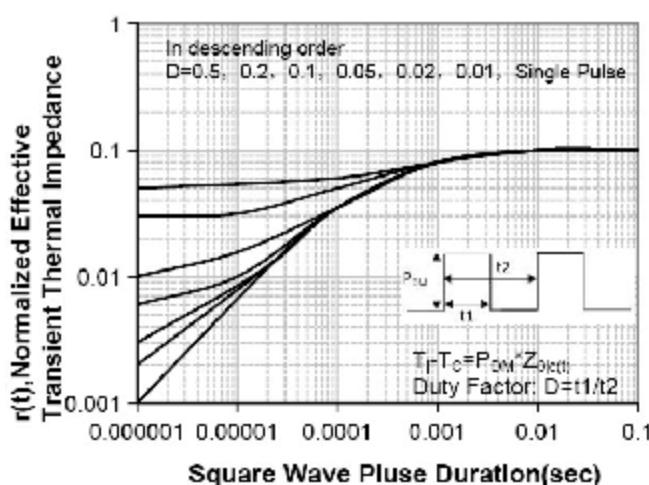
**Figure 8. On-Resistance Variation vs Gate Voltage**



**Figure 9. Maximum Safe Operating Area**



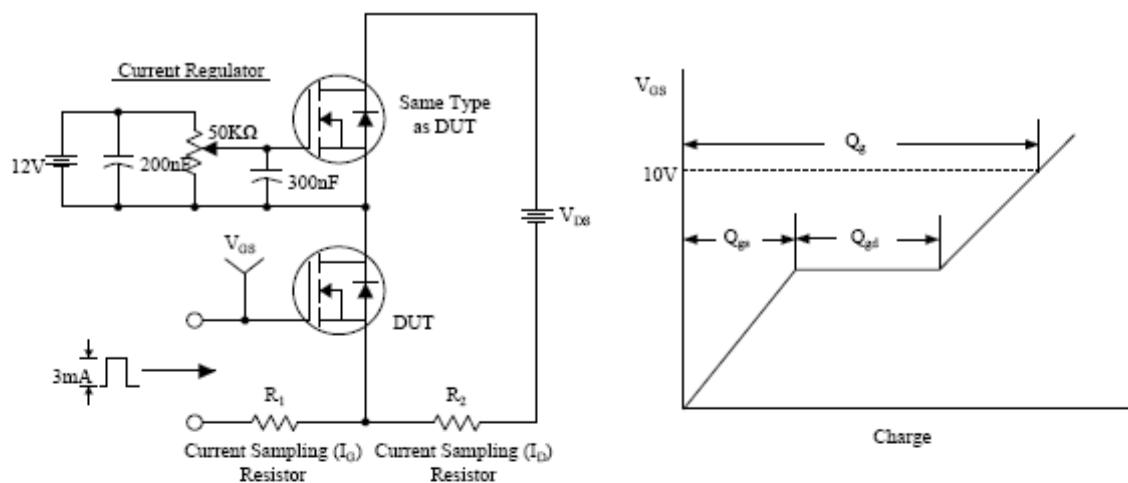
**Figure 10. Maximum Continuous Drain Current vs Case Temperature**



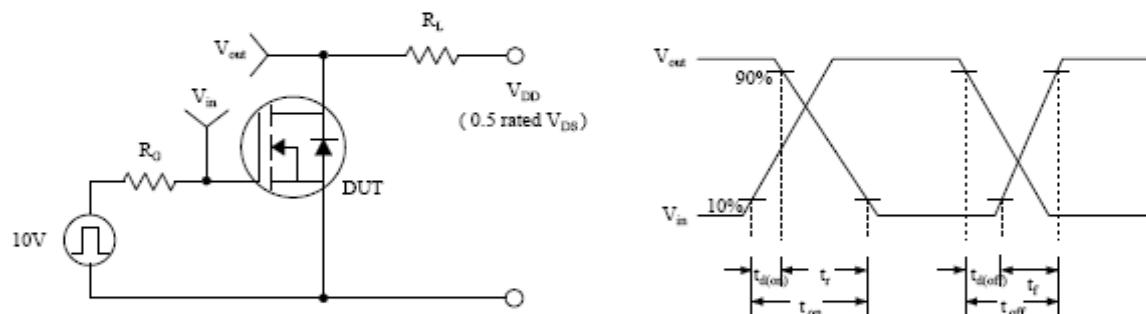
**Figure 11. Transient Thermal Response Curve**

## 9. Test Circuits and Waveforms

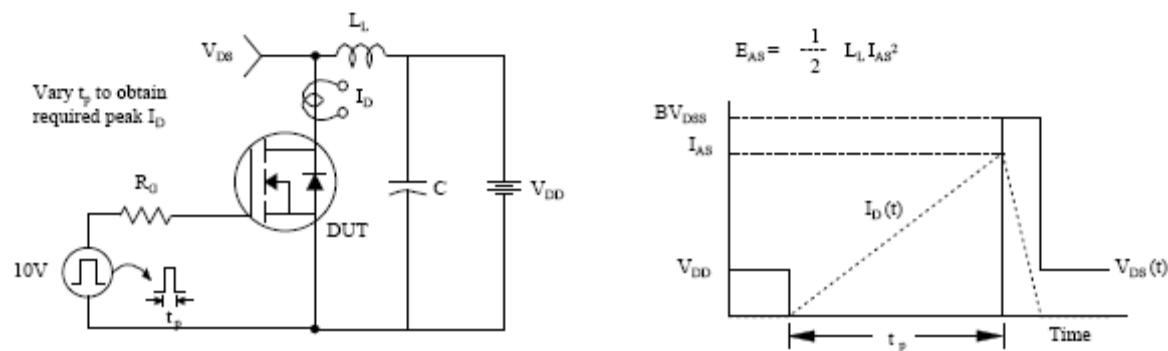
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



## Peak Diode Recovery dv/dt Test Circuit & Waveforms

